

1. Record Nr.	UNISA996216505403316
Titolo	The 23rd IEEE International Symposium on Defect and Fault-Tolerance in VLSI Systems : proceedings : Boston, Massachusetts, 1-3 October 2008 / / edited by Cristiana Bolchini, Yong-Bin Kim, Dimitris Gizopoulos, and Mohammad Tehranipoor ; sponsored by The IEEE Computer Society Test Technology Technical Council, The IEEE Computer Society Technical Committee on Fault Tolerant Computing
Pubbl/distr/stampa	New York : , : IEEE, , 2008
ISBN	1-5090-8441-X
Descrizione fisica	1 online resource (xxxi, 545 pages)
Soggetti	Integrated circuits - Very large scale integration - Design and construction Fault-tolerant computing
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Includes index.